


<b>Search Notes</b> 	<b>Application/Control No.</b> 09900784	<b>Applicant(s)/Patent Under Reexamination</b> WASHINO ET AL.
	<b>Examiner</b> M. Lee	<b>Art Unit</b> 2622

SEARCHED			
Class	Subclass	Date	Examiner
348	722, 231-23	9/13/08	ML
386	117-120, 52-60	9/13/08	ML
360	14.1, 14.3	9/13/08	ML
H04N	5/46	9/13/08	ML

SEARCH NOTES		
Search Notes	Date	Examiner
east	9/13/08	ML

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/M. Lee/ Primary Examiner.Art Unit 2622
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